

**Notice of References Cited**

Application/Control No.

10/554,383

Applicant(s)/Patent Under  
Reexamination  
VRANKEN ET AL.

Examiner

DANIEL F. MCMAHON

Art Unit

4146

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0099992	07-2002	Distler et al.	714/738
*	B	US-2007/0067688	03-2007	Vranken et al.	714/733
*	C	US-2002/0162066	10-2002	Khoche et al.	714/738
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sying-Jyan Wang; Sheng-Nan Chiou, "Generating efficient tests for continuous scan," 2001, Design Automation Conference, 2001. Proceedings - vol., no., pp. 162-165
	V	Venkataraman, S.; Rajski, J.; Hellebrand, S.; Tarnick, S., "An Efficient Bist Scheme Based On Reseeding Of Multiple Polynomial Linear Feedback Shift Registers," Computer-Aided Design, 1993. ICCAD-93. Digest of Technical Papers., 1993 IEEE/ACM International Conference on, vol. no., pp 572-577, 7-11 Nov 1993
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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